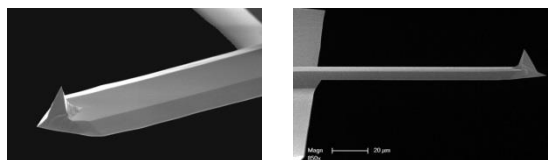
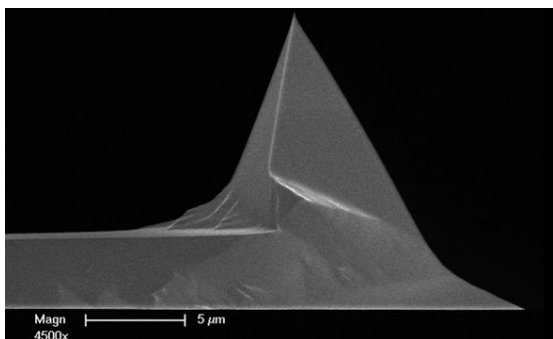


NCHV

General Tapping,
Non-Contact AFM Probes



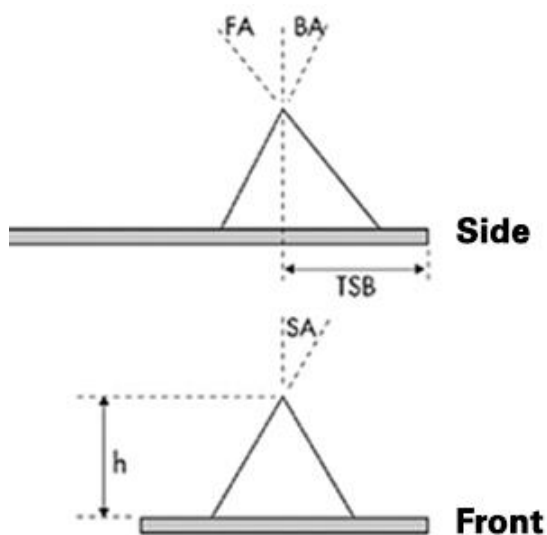
Models

10-Pack
No Reflex
Coating

Wafer
No Reflex
Coating

10-Pack
Al Reflex
Coating

Wafer
Al Reflex
Coating



Product Description

Value Line etched Silicon probes for imaging in TappingMode and non-contact mode in air.

Specifications: 40 N/m, 320 kHz, 8 nm tip radius, no reflex coating.

- 10 probes per pack.
- Compatible with most commercially available AFMs.

Tip Specification

Geometry:	Standard (Steep)
Tip Height (h):	10 – 15 μm
Front Angle (FA):	25 ± 2.5°
Back Angle (BA):	15 ± 2.5°
Side Angle (SA):	22.5 ± 2.5°
Tip Radius (Nom):	8 nm
Tip Radius (Max):	10 nm
Tip Set Back (TSB)(Nom):	12.5 μm
Tip Set Back (TSB)(RNG):	9 - 16 μm

Cantilever Specification

Material:	0.01 - 0.025 Ωcm Antimony (n) doped Si
Geometry:	Rectangular
Cantilevers Number:	1
Cantilever Thickness (Nom):	3.5 μm
Cantilever Thickness (RNG):	2.8 - 4.2 μm

For more information email:
afmprobeorders@bruker.com or visit:

ValueAFMProbes.com